




RADIO TEST REPORT


Test Report No. : 31FE0131-HO-01-A-R1

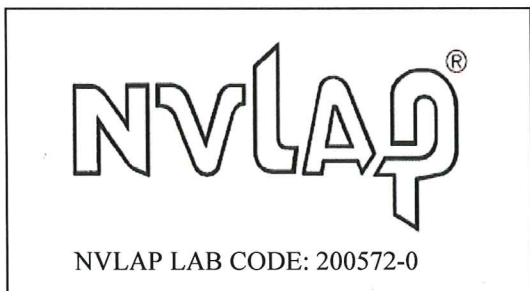
Applicant : SINFONIA TECHNOLOGY CO., LTD.
Type of Equipment : Digital Photo Printer
Model No. : CHC-S2145-5
Test standard : FCC Part 15 Subpart C: 2011
FCC ID : ZQUCHC-S2145-5
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This report is a revised version of 31FE0131-HO-01-A. 31FE0131-HO-01-A is replaced with this report.

Date of test: July 23 and 24, 2011

Representative test engineer: 
Takeshi Choda
Engineer of WiSE Japan,
UL Verification Service

Approved by: 
Mitsuru Fujimura
Leader of WiSE Japan,
UL Verification Service



This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address, <http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

CONTENTS	PAGE
SECTION 1: Customer information	3
SECTION 2: Equipment under test (E.U.T.)	3
SECTION 3: Test specification, procedures & results	4
SECTION 4: Operation of E.U.T. during testing	7
SECTION 5: Conducted emission	9
SECTION 6: Radiated emission (Fundamental, Spurious Emission and Spectrum Mask)	10
SECTION 7: Other test	11
APPENDIX 1: Photographs of test setup	12
Conducted emission	12
Radiated emission	13
APPENDIX 2: Data of EMI test	14
Conducted emission	14
Fundamental emission and Spectrum Mask.....	15
Spurious emission	16
Frequency Tolerance	20
APPENDIX 3: Test instruments	21

SECTION 1: Customer information

Company Name : SINFONIA TECHNOLOGY CO., LTD.
Address : 100 Takegahana-cho, Ise-shi, Mie-ken, 516-8550 JAPAN
Telephone Number : 81-596-36-1286
Facsimile Number : 81-596-36-3884
Contact Person : Tsutomu Inagaki

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Digital Photo Printer
Model No. : CHC-S2145-5
Serial No. : Refer to Section 4, Clause 4.2
Rating : AC 100-240V, 50/60Hz, 4.8A
Receipt Date of Sample : July 22, 2011
Country of Manufacture : Japan
Condition of EUT : Production model
Modification of EUT : No Modification by the test lab

2.2 Product Description

General Specification

The clock frequency used in EUT : External 50MHz: Internal CPU 100MHz, FPGA 50MHz, DSP 200MHz
External 24MHz: Internal USB Communicate with PC at maximum 480MHz
External 13.56MHz: Internal RFID 13.56MHz

Radio Specification

Radio Type : Transceiver
Frequency of Operation : 13.56MHz
Modulation : ASK
Power Supply (radio part input) : DC 3.3V
Antenna type : Pattern Antenna
Antenna Connector : BNC

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2011, final revised on July 8, 2011 and effective August 8, 2011

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.225 : Operation within the band 13.110-14.010MHz

*The revision on July 8, 2011 does not affect the test specification applied to the EUT.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted emission	ANSI C63.4:2003 7. AC powerline conducted emission measurements ----- <IC>RSS-Gen 7.2.4	Section 15.207 ----- <IC>RSS-Gen 7.2.4	[QP] 8.4dB 16.03120MHz, L [AV] 8.3dB 0.17244MHz, N	Complied	-
Electric Field Strength of Fundamental Emission	ANSI C63.4:2003 13. Measurement of intentional radiators ----- <IC> RSS-Gen 4.8, 4.11	Section 15.225(a) ----- <IC>RSS-210 A2.6	89.1dB 13.56000MHz, QP, 0deg.	Complied	Radiated
Spectrum Mask	ANSI C63.4:2003 13. Measurement of intentional radiators ----- <IC>RSS-Gen 4.9, 4.11	Section 15.225(b)(c) ----- <IC> RSS-210 A2.6	46.3dB 14.01000MHz, QP, 0deg.	Complied	Radiated
20dB Bandwidth	ANSI C63.4:2003 13. Measurement of intentional radiators ----- <IC> -	Section15.215(c) ----- <IC> -	See data	Complied	Radiated
Electric Field Strength of Spurious Emission	ANSI C63.4:2003 13. Measurement of intentional radiators ----- <IC>RSS-Gen 4.9, 4.11	Section15.209, Section 15.225 (d) ----- <IC>RSS-210 A2.6	12.8dB 350.001MHz, Horizontal, QP 10.7dB *1) 480.002MHz, Vertical, QP	Complied	Radiated
Frequency Tolerance	ANSI C63.4:2003 13. Measurement of intentional radiators ----- <IC>RSS-Gen 4.7	Section15.225(e) ----- <IC> RSS-210 A2.6	See data	Complied	Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No.: 13-EM-W0420 and 13-EM-W0422

*1) This is noise other than radio part.

FCC 15.31 (e)

This EUT provides stable voltage (DC 3.3V) constantly to RF Part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Band Width	RSS-Gen 4.6.1	RSS-Gen 4.6.1	N/A	-	Radiated

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.1dB
No.2	3.3dB
No.3	3.7dB
No.4	3.2dB

Test room (semi-anechoic chamber)	Radiated emission (10m*)(±dB)		
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz
No.1	3.3dB	5.2dB	5.2dB
No.2	-	-	-
No.3	-	-	-
No.4	-	-	-

*10m = Measurement distance

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	3.5dB	5.1dB	5.2dB	4.8dB	5.1dB	4.4dB	4.3dB
No.2	4.0dB	5.1dB	5.2dB	4.8dB	5.0dB	4.3dB	4.2dB
No.3	4.2dB	4.7dB	5.2dB	4.8dB	5.0dB	4.5dB	4.2dB
No.4	4.0dB	5.0dB	5.1dB	4.8dB	5.0dB	5.1dB	4.2dB

3m/1m/0.5m = Measurement distance

Frequency counter (+)	
Normal condition	Extreme condition
7×10^{-6}	9×10^{-6}

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test (3m and 10m)

The data listed in this test report has enough margin, more than the site margin.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

The mode is used :

Mode	Remarks
Transmitting (Tx and Rx) mode	Modulation off (Mod off)
The EUT was operated in a manner similar to typical use during the tests. The EUT Transmits and Receives at the same time and there is no receiving mode.	
*Power Setting: Same as production model Software: E0208100-1312 Any conditions under the normal use do not exceed the condition of setting. In addition, end users cannot change the settings of the output power of the product.	

Test Item	Operating mode
Conducted emission	Transmitting (Tx and Rx)
Electric Field Strength of Fundamental Emission	Transmitting (Tx and Rx)
Spectrum Mask	Transmitting (Tx and Rx)
20dB Bandwidth	Transmitting (Tx and Rx)
Electric Field Strength of Spurious Emission	Transmitting (Tx and Rx)
Frequency Tolerance	Transmitting (Tx and Rx), Mod off

Justification: The system was configured in typical fashion (as a customer would normally use it) for testing.

Frequency Tolerance:

Temperature : -30deg.C to +50deg.C Step 10deg.C
Voltage : Normal Voltage AC 120V (Rating: AC 100 - 240V)
Maximum Voltage AC 276V(AC 240V +15%),
Minimum Voltage AC 85V (AC 100V -15%)

*This EUT provides stable voltage (DC 3.3V) constantly to RF Part regardless of input voltage.

UL Japan, Inc.

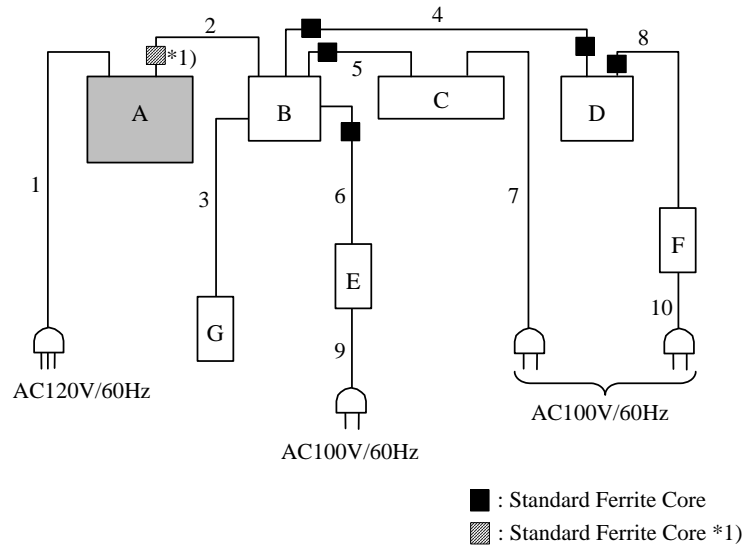
Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

4.2 Configuration and peripherals



* Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Digital Photo Printer	CHC-S2145-5	E629	SINFONIA TECHNOLOGY CO., LTD.	EUT
B	Laptop PC	2668-D59	L3-YWXVY	IBM	-
C	Monitor	E173FPC	CN-0D5431-64180-59T-197C	DELL	-
D	Printer	C6414A	CNDB11C1H2	HP	-
E	AC Adapter	02K6757	11S02K6750Z1Z2U P29909T	IBM	-
F	AC Adapter	C6409-60014	AA21210	HP	-
G	USB Mouse	M-UB48	830318-0000	Logitech	-

List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	AC Cable	3.0	Unshielded	Unshielded	-
2	USB Cable	1.5	Shielded	Shielded	-
3	Mouse Cable	0.8	Shielded	Shielded	-
4	Printer Cable	2.0	Shielded	Shielded	-
5	RGB Cable	1.8	Shielded	Shielded	-
6	DC Cable	1.6	Unshielded	Unshielded	-
7	AC Cable	1.7	Unshielded	Unshielded	-
8	DC Cable	2.0	Unshielded	Unshielded	-
9	AC Cable	2.0	Unshielded	Unshielded	-
10	AC Cable	1.8	Unshielded	Unshielded	-

<Notes for Ferrite cores>

*1) 1 Ferrite Core, Model No. ESD-SR-160 (Manufacturer: NEC-TOKIN), 3cm from Item A, 2 turns
This core is included with end product and the mounting instruction is written on the user manual.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 5: Conducted emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 2.0m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector : QP and AV
Measurement range : 0.15-30MHz
Test data : APPENDIX
Test result : Pass

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 6: Radiated emission (Fundamental, Spurious Emission and Spectrum Mask)

Test Procedure

EUT was placed on a urethane platform of nominal size, 1.0m by 2.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane. The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength. The measurements were performed for both vertical (angle of loop antenna: 0deg., 45deg., 90deg., and 135 deg.) and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer. The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode). The test was made with the detector (RBW/VBW) in the following table. When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

Frequency	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz	Above 1GHz	
Instrument used	Test Receiver					Spectrum Analyzer	
Detector	PK/AV	QP	PK/AV	QP	QP	PK	AV
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz

The test was made on EUT at the normal use position.

Measurement range : 9kHz-1GHz
Test data : APPENDIX
Test result : Pass

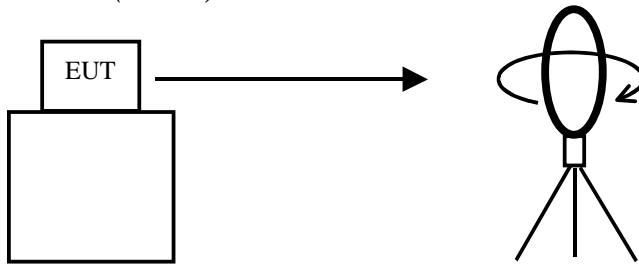
SECTION 7: Other test

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	1MHz	10kHz	30kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Sample	Clear Write	Spectrum Analyzer
Frequency Tolerance	-	-	-	-	-	-	Spectrum Analyzer

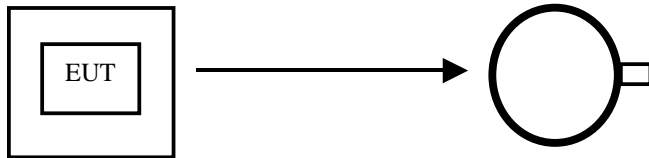
Test data : APPENDIX
Test result : Pass

Figure 1: Direction of the Loop Antenna

Side View (Vertical)

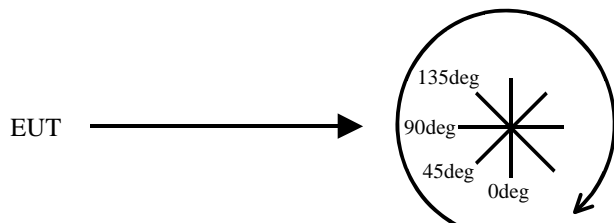


Top View (Horizontal)



Antenna was not rotated.

Top View (Vertical)



Front side: 0 deg.
Forward direction: clockwise